- 2:30 D-22 Crystal Structures of BaSrR₄Zn₂O₁₀, R = La, Nd, Sm, Eu J.A. Kaduk, *Poly Crystallography, Naperville, IL* W. Wong-Ng, *NIST, Gaithersburg, MD*
- 2:50 D-60 Detection and Quantification of Passivation Layers in Electrochemical Inert Anodes by In-Situ and Ex-Situ Diffraction

M.R. Rowles, K. McGregor, G.A. Snook, CSIRO Process Science and Engineering/CSIRO Light Metals Flagship, Victoria, Australia

I.C. Madsen, N.V.Y. Scarlett, M. Lanyon, A. Urban, CSIRO Process Science and Engineering, Victoria, Australia M.J. Styles, D.P. Riley, The University of Melbourne, Victoria, Australia

3:10 Break

3:40 C-6 Characterization of X-ray Powder Diffraction Data of Ba_xSr_{1-x}SO₄ (0≤ x≤1) by Rietveld Refinement

S.R. Zaidi, H. Sitepu, S. Shen, N. Al-Yami, Saudi ARAMCO, Dhahran, Saudi Arabia

- 4:00 D-77 XRD Anisotropic Broadening of Nano-Particles Y. Wang, S.L.I. Chan, Y.R. Shen, R. Amal, K. Kiatkittipong, *University of New South Wales, Australia*
- 4:20 D-19 Differences between Near-Surface and Bulk Preferred Orientation with Powder Diffraction Data of Molybdite (MoO₃) and Calcite (CaCO₃)
 H. Sitepu, Curtin University of Technology, Perth, Australia and Saudi ARAMCO, Dhahran, Saudi Arabia B.H. O'Connor, D. Li, Curtin University of Technology, Perth, Australia
- 4:40 D-13 Computational Texture Analysis with MTEX R. Hielscher, Technische Universitaet Chemnitz, Germany F. Bachmann, H. Schaeben, Technische Universitaet Bergakademie Freiberg, Germany

THURSDAY PM

XRD

MICRO DIFFRACTION

EVERGREEN D

Chair: C. Murray, IBM, T.J. Watson Research Center, Yorktown Heights, NY

- 2:00 D-20 Invited—Three Dimensional X-ray Diffraction Microscopy L. Margulies, Brookhaven National Laboratory, Upton, NY H.F. Poulsen, S. Schmidt, D.J. Jensen, Risoe National Lab, Roskilde, Denmark G. Vaughan, J. Wright, ESRF, Grenoble, France
- 2:30 D-30 Invited—Nanoscale Scanning Probe Diffraction Microscopy at the Hard X-ray Nanoprobe Beamline
 - M. Holt, S. Hruszkewycz, R. Winarski, V. Rose, J. Maser, Argonne National Laboratory, Argonne, IL
- 3:00 D-81 Multi-Dimensional X-ray Investigation of Materials—Ranging from Classical Bragg-Brentano Type Diffraction Phase Analysis to 3 Dimensional CT Microstructure Analysis
 - H. Pöllmann, University of Halle/Mineralogy, Halle, Germany
 - R. Maier, U. Riedl, G. Blaj, PANalytical, Almelo, The Netherlands